

Resource Summary Report

Generated by [RRID](#) on Aug 6, 2026

FEI: Themis S S/TEM for Semiconductors

RRID:SCR_019909

Type: Tool

Proper Citation

FEI: Themis S S/TEM for Semiconductors (RRID:SCR_019909)

Resource Information

URL: <https://www.fei.com/products/tem/themis-s-for-semiconductors/>

Proper Citation: FEI: Themis S S/TEM for Semiconductors (RRID:SCR_019909)

Description: Scanning/transmission electron microscope that is designed for high-speed imaging and analysis of semiconductor devices.

Resource Type: instrument resource

Keywords: FEI, TEM, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: Themis S S/TEM for Semiconductors

Resource ID: SCR_019909

Alternate IDs: Model_Number_Themis S

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260801T190648+0000

Ratings and Alerts

No rating or validation information has been found for FEI: Themis S S/TEM for Semiconductors.

No alerts have been found for FEI: Themis S S/TEM for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.